

PROCEEDINGS OF SPIE

X-Ray Free-Electron Lasers: Advances in Source Development and Instrumentation VII

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8–10 April 2025
Prague, Czech Republic

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Published by
SPIE

Volume 13536

Proceedings of SPIE 0277-786X, V. 13536

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

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Please use the following format to cite material from these proceedings:

Author(s), "Title of Paper," in *X-Ray Free-Electron Lasers: Advances in Source Development and Instrumentation VII*, edited by Thomas Tschentscher, Luc Patthey, Kai Tiedtke, Marco Zangrando, Proc. of SPIE 13536, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510688681

ISBN: 9781510688698 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

SPIE.org

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Contents

v *Conference Committee*

UPDATES ON FACILITIES AND NEW FEL SOURCES

- 13536 03 **Laser-plasma-accelerator-based compact free electron laser at ELI-Beamlines** [13536-5]
- 13536 04 **Operation of the variable polarization undulator on the third harmonic of a SASE FEL**
[13536-6]

ADVANCED LASING SOURCES AND TECHNIQUES

- 13536 05 **The superconducting undulator development program at the European XFEL** [13536-12]

ATTOSECOND FEL RADIATION PULSES

- 13536 06 **Hard x-ray attosecond pulses at the LCLS** [13536-14]
- 13536 07 **Instrumental effects on attosecond XFEL pulses temporal diagnostics** [13536-16]

PHYSICAL AND VIRTUAL DIAGNOSTICS OF FEL BEAMS

- 13536 08 **Towards data-driven surrogate models of the European XFEL** [13536-21]

X-RAY OPTICS AND WAVEFRONT SENSING

- 13536 09 **Preliminary characterization of a plasma-polished channel cut for future monochromator applications at European XFEL** [13536-24]
- 13536 0A **Design of a wavefront sensor for nanofocusing characterization at SHINE** [13536-28]

FEL SCIENCE APPLICATIONS I

- 13536 0B **Nanoscale structured illumination microscopy with ultrafast extreme-ultraviolet transient gratings (Invited Paper)** [13536-29]
- 13536 0C **Liquid sheets and heterostructures for FEL and laser applications** [13536-33]

FEL SCIENCE APPLICATIONS II

13536 0D **Single-pulse in-line holography for ultrafast imaging of extended objects with 10nm resolution** [13536-35]

POSTER SESSION

13536 0E **Demonstration of space-charge-enhanced energy modulation at FERMI** [13536-48]